


<b>Search Notes</b>  	<b>Application/Control No.</b>  10714397	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Cehic, Kenan	<b>Art Unit</b>  2616

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	271, 352-356	2/14/2008	KC

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventorship search	2/6/2008	KC
Consulted with SPE Kwang Yao	2/4/2008	KC

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>